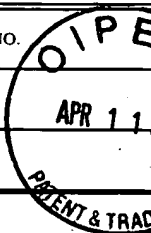


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. M122-1299		SERIAL NO. 09/428.125	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Micron Technology, Inc.			
					FILING DATE October 26, 1999		GROUP 2822	
U.S. PATENT DOCUMENTS								
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
<div style="font-size: 2em;">K</div>	AA	5,411,912	5-2-95	Sakamoto				
	AB	5,508,221	4-16-96	Kamiyama				
	AC	5,876,788	3-2-99	Bronner				
	AD	6,010,931	1-4-00	Sun et al.				
	AE	6,037,205	3-14-00	Huh et al.				
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	AG	6,150,208	11-21-00	Deboer et al.				
	AH	6,150,706	11-21-00	Thakur et al.				
	AI	6,168,985	1-2-01	Asano et al.				
	AJ	6,180,481	1-30-01	DeBoer				
<div style="font-size: 2em;">K</div>	AK	6,197,653	3-6-01	Khamankar				
	AL							
FOREIGN PATENT DOCUMENTS								
	Document Number	Date	Country	Class	Subclass	Translation		
						Yes	No	
<div style="font-size: 2em;">K</div>	AM	407161827A		Japan				
	AN	405211288A		Japan				
	AO							
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR							
	AS							
	AT							
EXAMINER <i>A. Rose</i>				DATE CONSIDERED <i>6/12/03</i>				
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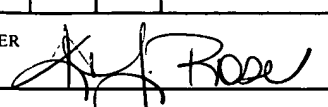
Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1299	SERIAL NO. 09/428,125
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RR	AA	5,834,060	11-1998	Kawahara et al.			
	AB	5,760,474	06-1998	Schuele			
	AC	5,864,496	01-1999	Mueller et al.			
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	AK						
	AL						

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*Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
RR	AM	04162527A	06-1992	Japan			
RR	AN	403209869A	09-1991	Japan			
	AO						
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*Examiner Initial	AR	Van Zant, "Microchip Fabrication: A Practical Guide to Semiconductor Processing" 4 th Edition, McGraw Hill 2000, pgs. 388-389.	
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